**STAT 5340-001**

**Fall 2023**

**Workshop 2 – Two Sample Inference and Estimation**

In Workshop 1, it was discovered that gate width results were more variable on C Shift than some of the others (especially B & D Shifts). As a result, what might be different about this shift was explored and one of the discoveries was that it appeared the product measured on C Shift was more often split across two different measurement tools (SEM 1 and SEM 2), while on the night shifts (B & D) the operators generally utilized only one SEM tool.

This observation suggested that this might explain the more variable results observed for the results generated on C Shift. In order to verify this, 15 wafers produced on C Shift were measured on each of SEM 1 and SEM 2. Your management is expecting a summary of these test results.

Your team needs to evaluate the data obtained as described above and report back to management on any potentially relevant findings.

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| Workshop 2 | Team 1 | Team 2 | Team 3 |
| Data Set | 1 | 2 | 3 |
| Members | Victor | Sidhu | Vivek |
| Job | Sneha | Clark |
| Jaliyah | Steven | Jaslynn |